HEIWA.026AUS PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Noriaki Chiba ) Group Art Unit )
Serial No. : New Application )

Filed : Concurrently Herewith

For : TIMING GENERATION CIRCUIT

AND SEMICONDUCTOR TEST DEVICE HAVING THE TIMING

GENERATION CIRCUIT

Examiner : Unknown

## PRELIMINARY AMENDMENT

Hon. Commissioner of Patents and Trademarks Alexandria, VA 22313-1450

## Dear Sir:

This amendment is submitted for the above-identified patent application for correcting the forms of the claims. Please make the following changes.